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PATENT APPLICATION  
IAP9 Rec'd PCT/PTO 19 DEC 2005

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IN THE U.S. PATENT AND TRADEMARK OFFICE

December 16, 2005

Applicant(s) : Stefan FABER et al.  
For : MIXED METAL OXIDES AND USE THEREOF IN CO<sub>2</sub>  
SENSORS

PCT International Application No.: PCT/EP2004/006938

PCT International Filing Date: June 25, 2004

U.S. Application No.

(if known, see 37 CFR 1.5): Unknown

Atty. Docket No.: 5000.P0090US

Mail Stop PCT  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

#### INFORMATION DISCLOSURE STATEMENT

Sir:

In compliance with the provisions of Rules 1.97(b)(2) and 1.98, enclosed herewith is a copy of the International Patent Office Search Report for the foreign patent application corresponding to the present application, Form PTO-1449 and the non-U.S. references cited thereon. Copies of cited U.S. references are not submitted in accordance with 37 CFR 1.98(a).

Where necessary, the requirement for a concise explanation of relevance of any enclosed non-English reference is satisfied by the enclosed International Patent Office Search Report. Further comment at this point in time should not be necessary.

Further consideration is respectfully solicited.

Respectfully submitted,

TFC/alh

  
Terryence F. Chapman

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Encl: Form PTO-1449 and non-U.S. references cited thereon

INFORMATION  
DISCLOSURE  
CITATION

Applicant: Stefan FABER et al.

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Group: Unknown

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## U.S. PATENT DOCUMENTS

Examiner Initials*	Cite No.	Document Number - Kind Code	Publication Date MM-DD-YYYY	Name of Patentee or Applicant
	AA	6 533 966 B1	03-18-2003	Nonninger et al.
	AB			

## FOREIGN PATENT DOCUMENTS

Examiner Initials*	Cite No.	Country Code - Document Number - Kind Code	Publication Date MM-DD-YYYY	Name of Patentee or Applicant	Trans.
	AC	DE 44 37 692 A1	04-25-1996	Haeusler et al.	Abstract
	AD	EP 0 263 394 A2	04-13-1988	Kazuko et al.	
	AE	EP 0 761 601 A1	03-12-1997	Yao	
	AF	GB 2 206 571 A	01-11-1989	Bonanos et al.	
	AG	WO 00/03947	01-27-2000	Kaliaguine et al.	

## NON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No.	(Include Author, Title, Date, Pages, Etc.)
	AH	International Search Report dated September 23, 2004 (3 pages)
	AI	German Office Action dated February 19, 2004 (3 pages)
	AJ	"Giant capacitance effect and physical model of nano crystalline CuO-BaTiO <sub>3</sub> semiconductor as a CO <sub>2</sub> gas sensor" (7 pages), by Q. Wei et al., October 15, 2000, from the Journal of Applied Physics, Volume 88, Number 8
	AK	"Sol-Gel Synthesis of Nano-Scaled BaTiO <sub>3</sub> , BaZrO <sub>3</sub> and BaTi <sub>0.5</sub> Zr <sub>0.5</sub> O <sub>3</sub> Oxides via Single-Source Alkoxide Precursors and Semi-Alkoxide Routes" (14 pages), by Michael Veith et al., August 27, 1999
	AL	"Heterometal Alkoxides: Precursors for Ceramic Materials" (11 pages), by Ram C. Mehrotra, September/October 1990, from Chemtracts-Analytical, Physical, and Inorganic Chemistry 2:389-399 (1990)

EXAMINER SIGNATURE

DATE CONSIDERED

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.